

What is claimed is:

1 1. An integrated circuit on a chip, comprising:
2 a substrate; and
3 at least one scan chain disposed in the substrate, with
4 scan cells connected to form a series chain, each
5 connection being formed according to a layout
6 constraint with a minimum dimension provided by
7 design rules for an assigned routing layer.

1 2. The integrated circuit as claimed in claim 1,
2 wherein the assigned routing layer is a first metal layer.

1 3. The integrated circuit as claimed in claim 2,
2 wherein the layout constraint limits the connection to passage
3 through at least the first metal layer.

1 4. The integrated circuit as claimed in claim 3,
2 wherein the layout constraint limits the connection to passage
3 through only the first metal layer.

1 5. The integrated circuit as claimed in claim 3,
2 wherein the layout constraint limits each metal line of the
3 first metal layer, to form the connection, to line width of
4 critical dimension (CD) of the first metal layer.

1 6. The integrated circuit as claimed in claim 3,
2 wherein the layout constraint further limits any metal line
3 of a second metal layer in the connection to a line width
4 exceeding CD of the second metal layer.

1 7. The integrated circuit as claimed in claim 3,
2 wherein the layout constraint further requires any plug of
3 a plug layer linking two metal lines in the connection to be
4 more than one.

1 8. The integrated circuit as claimed in claim 1,
2 wherein the assigned routing layer is a plug layer.

1 9. The integrated circuit as claimed in claim 8,
2 wherein the layout constraint limits the connection to passage
3 through at least the plug layer and plugs of the plug layer,
4 linking two metal lines in the connection, to one only.

1 10. The integrated circuit as claimed in claim 9,
2 wherein the layout constraint further limits any metal line
3 of a metal layer in the connection to a line width exceeding
4 CD of the metal layer.

1 11. The integrated circuit as claimed in claim 1,
2 wherein the integrated circuit further has an auxiliary
3 routing net positioned in parallel beside the scan chain, the
4 auxiliary routing net has metal lines of different lengths,
5 and the auxiliary routing net does not function when the scan
6 chain is originally formed.

1 12. The integrated circuit as claimed in claim 11,
2 wherein one of the metal lines has sufficient length to replace
3 one of the connections in the scan chain.

1 13. The integrated circuit as claimed in claim 11,
2 wherein one of the metal lines has a length equal to at least
3 two scan cells in the scan chain.